

JP525 U.S. PTO
09/535,836
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LIST OF PUBLICATIONS CITED BY APPLICANT			Attorney Docket No. SEL 173	Serial No. Not Assigned 09/535,836		
			Applicant Hisashi OHTANI et al			
			Filing Date Herewith 03/28/00	Group 28W		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
V _h	5,594,569	01/14/97	Konuma et al	349	122	07/20/94
V _h	5,643,826	07/01/97	Ohtani et al	437	88	10/25/94
V _h	5,648,277	07/15/97	Zhang et al	437	21	11/02/94
V _h	5,923,962	07/13/99	Ohtani et al	438	150	04/28/95
FOREIGN PATENT DOCUMENT						
	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
V _h	JP 7-130652	05/19/95	Semiconductor Energy Laboratory Co., Ltd.			10/29/93
	JP 7-135318	05/23/95	Semiconductor Energy Laboratory Co., Ltd.			11/05/93
	JP 9-312260	12/02/97	Semiconductor Energy Laboratory Co., Ltd.			11/29/96
	JP 10-247735	09/14/98	Semiconductor Energy Laboratory Co., Ltd.			03/03/97
	JP 10-294280	11/04/98	Semiconductor Energy Laboratory Co., Ltd.			02/09/98
	JP 11-191628	07/13/99	Semiconductor Energy Laboratory Co., Ltd.			05/16/98
	JP 11-345767	12/14/99	Semiconductor Energy Laboratory Co., Ltd.			05/16/98
V _h	JP 11-354442	12/24/99	Semiconductor Energy Laboratory Co., Ltd.			05/15/98

OTHER PUBLICATIONS
(Including Author, Title, Date, Pertinent Pages)

V _u	<p>Yoshida, T. et al, "A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time," <i>SID 97 Digest</i>, pp. 841-844, 1997.</p> <p>Furue, H. et al, "Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCD Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability," <i>SID 98 Digest</i>, pp. 782-785, 1998.</p> <p>Hatano, M. et al, "A Novel Self-Aligned Gate-Overlapped IDD Poly-Si TFT with High Reliability and Performance," <i>IEDM Technical Digest 97</i>, pp. 523-526, 1997.</p> <p>English abstract re Japanese patent application no. 7-130652, published May 19, 1995.</p> <p>English abstract re Japanese patent application no. 7-135318 published May 23, 1995.</p> <p>English abstract re Japanese patent application no. 9-312260 published December 2, 1997.</p> <p>English abstract re Japanese patent application no. 10-247735, published September 14, 1998.</p> <p>English abstract re Japanese patent application no. 10-294280, published November 4, 1998.</p> <p>English abstract re Japanese patent application no. 11-191628, published July 13, 1999.</p> <p>English abstract re Japanese patent application no. 11-345767, published December 14, 1999.</p> <p>English abstract re Japanese patent application no. 11-354442, published December 24, 1999.</p>
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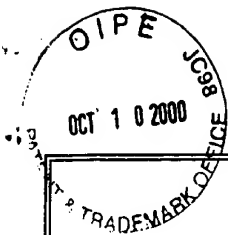
EXAMINER:

HUNG K. VU

DATE CONSIDERED:

06/21/01

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LIST OF PUBLICATIONS CITED BY APPLICANT			Attorney Docket No. SEL 173	Serial No. 09/535,836
			Applicant Hisashi OHTANI et al	
			Filing Date March 28, 2000	Group 1180 2611
U.S. PATENT DOCUMENTS				
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS SUB-CLASS FILING DATE
Vu	4,184,909	01/22/80	Chang et al	156 643 08/21/78
Vu	5,372,971	12/13/94	Kang et al	437 195 10/01/92
Vu	5,468,342	11/21/95	Nulty et al	156 643.1 04/28/94
Vu	5,868,951	02/09/99	Schuck, III et al	216 24 05/09/97
FOREIGN PATENT DOCUMENTS				
	DOCUMENT NUMBER	DATE	NAME	CLASS SUB-CLASS FILING DATE
Vu	GB 2 306 778	05/07/97	NEC Corporation	10/30/96
OTHER PUBLICATIONS (Including Author, Title, Date, Pertinent Pages)				
Vu	European Search Report re application no. EP 00 10 6863; published July 10, 2000.			
EXAMINER: HUNG K. VU			DATE CONSIDERED: 06/21/01	
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